

P-Channel 60 V (D-S) MOSFET

Py
RoHS

COMPLIANT

PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}$ (m Ω)(Typ.)	I _D (A) ^a	Q _g (Typ.)		
- 60	24 at V _{GS} = 10 V	10	76 00		
	31 at V _{GS} = 4.5 V	- 10	76 nC		

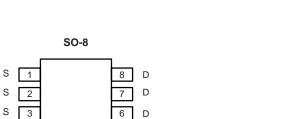
Top View

FEATURES

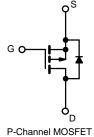
- DT-Trench Power MOSFET
- 100 % R_g and UIS Tested

APPLICATIONS

· Load Switch



D



Parameter		Symbol	Limit	Unit
Drain-Source Voltage		V _{DS}	- 60	V
Gate-Source Voltage		V _{GS}	± 20	V
Continuous Drain Current (T _J = 150 °C)	$T_C = 25 ^{\circ}\text{C}$ $T_C = 70 ^{\circ}\text{C}$	I-	- 10	
	T _C = 70 °C	I _D	- 7.3	Α
Pulsed Drain Current		I _{DM}	- 30	
Single-Pulse Avalanche Energy		E _{AS}	50	mJ
	T _C = 25 °C		15	
Maximum Dawar Dissination	T _C = 70 °C	P _D	9.6	W
Maximum Power Dissipation	T _A = 25 °C		2.5 ^{b,c}	VV
	T _A = 70 °C	1 -	1.6 ^{b,c}	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	°C

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^c	t ≤ 10 s	R _{thJA}	35	50	°C/W	
Maximum Junction-to-Case	Steady State	R_{thJC}	6.5	8.3		

Notes

- a. Based on T_C = 25 °C.
- b. Surface mounted on 1" x 1" FR4 board.
- c. t = 10 s.



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Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0, I _D = - 250 μA	- 60			V
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	- 1		- 3	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = - 60 V, V _{GS} = 0 V			- 1	μA
Zero Gate voltage Brain Guirent	DSS	V _{DS} = - 60 V, V _{GS} = 0 V, T _J = 55 °C			- 10	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge -10 \text{ V}, V_{GS} = -10 \text{ V}$	- 10			Α
Drain-Source On-State Resistance ^a	P	V _{GS} = - 10 V, I _D = - 5 A		24	29	mΩ
	R _{DS(on)}	V _{GS} = - 4.5 V, I _D = - 5 A		31	40	
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 15 V, I _D = - 5 A		45		S
Dynamic ^b			•			
Input Capacitance	C _{iss}			3510		pF
Output Capacitance	C _{oss}	$V_{DS} = -30 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		134		
Reverse Transfer Capacitance	C _{rss}			131		
Total Gate Charge	Qg			76		nC
Gate-Source Charge	Q _{gs}	$V_{DS} = -30 \text{ V}, V_{GS} = -10 \text{ V}, I_{D} = -5 \text{ A}$		16		
Gate-Drain Charge	Q _{gd}			19		
Gate Resistance	R _g	f = 1 MHz		5		Ω
Turn-On Delay Time	t _{d(on)}			12		
Rise Time	t _r	$V_{DD} = -30 \text{ V}, R_{L} = 2.0 \Omega$		7		- ns
Turn-Off DelayTime	t _{d(off)}	$I_D \cong -5 \text{ A}, V_{GEN} = -10 \text{ V}, R_g = 1 \Omega$		70		
Fall Time	t _f			40		
Drain-Source Body Diode Characterist	ics	•				
Continous Source-Drain Diode Current	Is	T _C = 25 °C			- 10	Α
Pulse Diode Forward Current (100 µs)	I _{SM}				- 30	_ ^
Body Diode Voltage	V_{SD}	I _S = - 1 A		- 0.6	- 1.2	V
Body Diode Reverse Recovery Time	t _{rr}			45		ns
Body Diode Reverse Recovery Charge	Q _{rr}	- I _F = - 5 A, dl/dt = 100 A/μs, T _{.I} = 25 °C		59		nC
Reverse Recovery Fall Time	t _a			29		ns
Reverse Recovery Rise Time	t _b			16		

Notes:

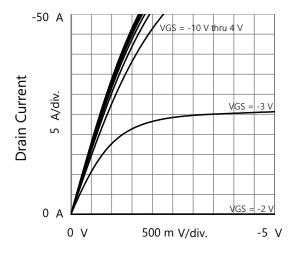
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$

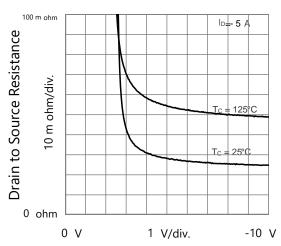
b. Guaranteed by design, not subject to production testing.



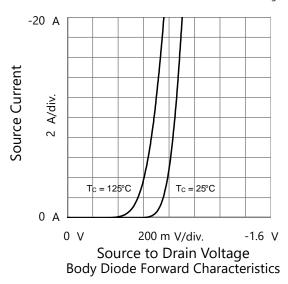
TYPICAL CHARACTERISTICS (25 C, unless otherwise noted)

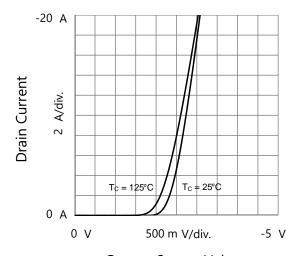


Drain to Source Voltage Output Characteristics

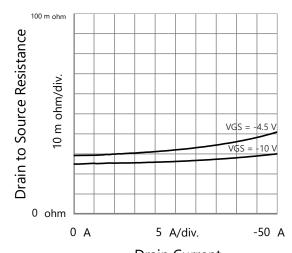


Gate to Source Voltage
Drain to Source Resistance vs. Gate to Source Voltage

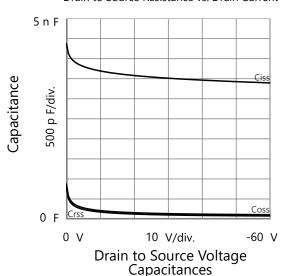




Gate to Source Voltage Transfer Characteristics

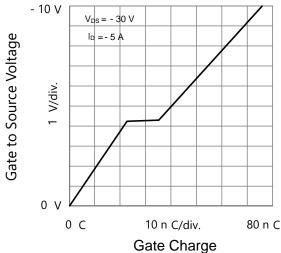


Drain Current
Drain to Source Resistance vs. Drain Current

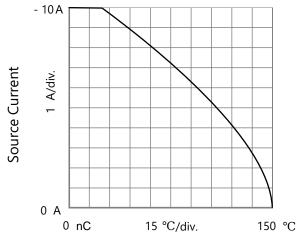




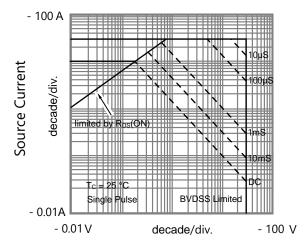
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



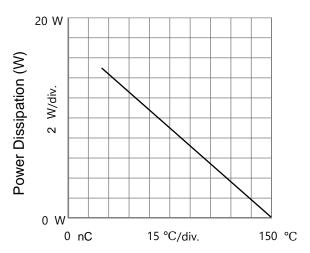
Gate Charge
Gate to Source Voltage vs. GateCharge



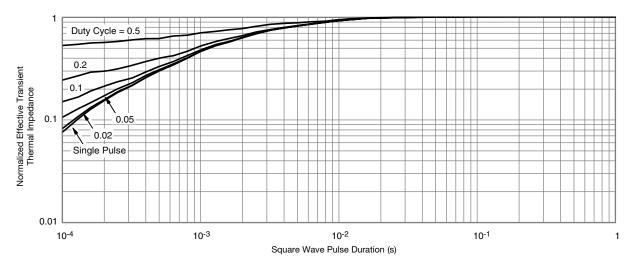
T_C - Case Temperature



Source to Drain Voltage Safe Operating Area, Junction-to-Ambient



T_C - Case Temperature



Normalized Thermal Transient Impedance, Junction-to-Case

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